	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	10047784	BARKER ET AL.
	Examiner	Art Unit
	Rutten, J. Derek	2192

	ORIGINAL	VAL			INTERN	INTERNATIONAL CLASSIFICATION	CLASSIFIC	ATION	
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J. Derek Rutten	2/26/07	20 Section 1	PCG				Tot	al Claims	Total Claims Allowed:
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